



3.3V Very Low Power 2-Output PCle Clock Generator With On-chip Termination

Features

- → 3.3V Supply Voltage
- → Crystal/CMOS input: 25 MHz
- → 2 Differential low power HCSL outputs with on-chip termination
- → Default $Z_{OUT} = 100Ω$
- → Individual output enable
- → Reference CMOS output
- → Programmable slew rate and output amplitude for each output
- → Differential outputs blocked until PLL is locked
- → Selectable 0%, -0.25% or -0.5% spread on differential outputs
- → Strapping pins or SMBus for configuration
- → Differential Output-To-Output Skew <50ps
- → Very-Low Jitter Outputs
 - Differential Cycle-To-Cycle Jitter <50ps
 - PCIe Gen1/Gen2/Gen3/Gen4/Gen5 Compliant
 - CMOS REFOUT Phase Jitter
 - < 0.3ps RMS, SSC off
 - <1.5ps RMS, SSC on
- → Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- → Halogen and Antimony Free. "Green" Device (Note 3)
- → For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

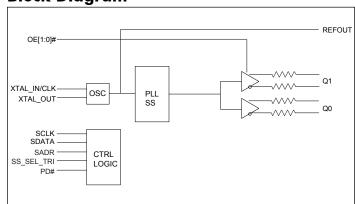
→ Packaging (Pb-free & Green): 24-lead 4×4mm TQFN

Description

The PI6CG33201C is a 2-output very low power PCIe Gen1/Gen2/Gen3/Gen4/Gen5 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low power differential HCSL outputs with on-chip terminations. The on-chip termination can save 8 external resistors and make layout easier. An additional buffered reference output is provided to serve as a low noise reference for other circuitry.

It uses Diodes' proprietary PLL design to achieve very low jitter that meets PCIe Gen1/Gen2/Gen3/Gen4/Gen5 requirements. It also provides various options such as different slew rate and amplitude through SMBUS so that users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spread-spectrum options to reduce EMI for various applications.

Block Diagram

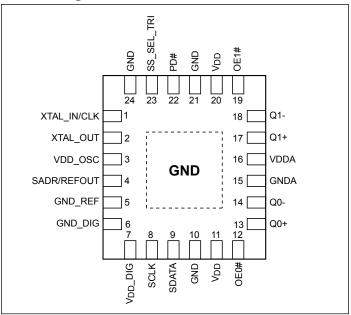


- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.





Pin Configuration



Pin Description

Pin #	Pin Name	Ту	pe	Description
1	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
2	XTAL_OUT	Output		Crystal output
3	V _{DD_OSC}	Power		Power supply for oscillation circuit, nominal 3.3V
4	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or LVCMOS REFOUT. This pin has an internal pull-down
5	GND_REF	Power		Ground for REFOUT
6	GND_DIG	Power		Ground for digital circuitry
7	V _{DD} _DIG	Power		Power supply for digital circuitry, nominal 3.3V
8	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
9	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
10, 21, 24	GND	Power		Ground pin
11, 20	V_{DD}	Power		Power supply, nominal 3.3V
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
15	GNDA	Power		Ground for analog circuitry
16	V_{DDA}	Power		Power supply for analog circuitry





Pin Description Cont.

Pin #	Pin Name	Ту	pe	Description
17	Q1+	Output	HCSL	Differential true clock output
18	Q1-	Output	HCSL	Differential complementary clock output
19	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs
22	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor.
23	SS_SEL_TRI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up. 1 = 0.5% spread, M = Spread off, 0 = Spread off. The pin has both internal pull-up and pull-down. Refer to SMBUS byte_1 bit 4, 3 = '01' to get -0.25% spread.
Epad	GND	Power		Connect to Ground





SMBus Address Selection Table

	SADR	Address	+Read/Write Bit
State of SADR on first application of PD#	0	1101000	X
	1	1101010	X

Power Management Table⁽³⁾

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	X	X	Low ⁽¹⁾	Low ⁽¹⁾	HiZ ⁽²⁾
1	1	0	Running	Running	Running
1	1	1	Disabled ⁽¹⁾	Disabled ⁽¹⁾	Running
1	0	X	Disabled ⁽¹⁾	Disabled ⁽¹⁾	Disabled ⁽⁴⁾

- 1. The output state is set by B11[1:0] (Low/Low default)
- 2. REF is Hi-Z until the 1st assertion of PD# high. After this, when PD# is low, REF is disabled. If Byte3, bit 5 = 1, then REF is running
- 3. Input High/ Low defined at default values for device
- 4. See SMBUs Byte 3, bit 4





Maximum Ratings

(Above which useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C
Supply Voltage to Ground Potential, V_{DDxx} 0.5V to +4.6V
Input Voltage $-0.5V$ to $V_{DD+0.5V}$, not exceed 4.6V
SMBus, Input High Voltage
ESD Protection (HBM)
Max Junction Temperature+125°C

Note: Stresses greater than those listed under MAXI-MUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Operating Conditions

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{DD} , V _{DDA} , V _{DD} OSC, V _{DD} DIG,	Power Supply Voltage		3.135	3.3	3.465	V
I_{DDA}	Analog Power Supply Current	All outputs active @100MHz		22	25	mA
I_{DD}	Power Supply Current ⁽³⁾	All V_{DD} , except V_{DDA} , All outputs active @100MHz		24	30	mA
I _{DDA_WL}	Analog Power Supply Wake-on- LAN ⁽¹⁾ Current	Q outputs off, REF output running		0.5	1.0	mA
$I_{\mathrm{DD_WL}}$	Power Supply Wake-on-LAN ⁽¹⁾ Current	All V_{DD} , except V_{DDA} , Q outputs off, REF output running		3.0	6.0	mA
I _{DDA_PD}	Analog Power Supply Power Down ⁽²⁾ Current	All outputs off		0.5	1.0	mA
I _{DD_PD}	Power Supply Power Down ⁽²⁾ Current	All outputs off		1.0	2.0	mA
T_{A}	Ambient Temperature	Industrial grade	-40		85	°C

- 1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'
- 2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'
- 3. Outputs drive 5 inch trace.





Input Electrical Characteristics

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R _{pu}	Internal pull up resistance			120		ΚΩ
R _{dn}	Internal pull down resistance			120		ΚΩ
C_{XTAL}	Internal capacitance on X_IN and X_OUT pins			8		pF
L _{PIN}	Pin inductance				7	nН

Crystal Characteristic

Parameters	Description	Min.	Тур	Max.	Units
OSCmode	Mode of Oscillation	F	undament	al	
FREQ	Frequency		25		MHz
ESR ⁽¹⁾	Equivalent Series Resistance			50	Ω
Cload	Load Capacitance		8		pF
Cshunt	Shunt Capacitance			7	pF
	Drive Level			200	uW

Note:

SMBus Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
$V_{ m DDSMB}$	Nominal bus voltage		2.7		3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1		3.6	
V _{IHSMB}	SMBus Input High Voltage	SMBus, V _{DDSMB} < 3.3V	0.65 V _{DDSMB}			V
17	CMD Lauret Laure Valle	SMBus, $V_{DDSMB} = 3.3V$			0.8	37
V_{ILSMB}	SMBus Input Low Voltage	SMBus, $V_{DDSMB} < 3.3V$	< 3.3V 0.8	0.8	V	
I _{SMBSINK}	SMBus sink current	SMBus, at V _{OLSMB}	4			mA
V _{OLSMB}	SMBus Output Low Voltage	SMBus, at I _{SMBSINK}			0.4	V
f_{MAXSMB}	SMBus operating frequency	Maximum frequency			500	kHz
t _{RMSB}	SMBus rise time	(Max V _{IL} - 0.15) to (Min V _{IH} + 0.15)			1000	ns
t _{FMSB}	SMBus fall time	(Min V_{IH} + 0.15) to (Max V_{IL} - 0.15)			300	ns

Spread Spectrum Characteristic

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f_{MOD}	SS Modulation Frequency	Triangular modulation	30	31.8	33	kHz

 $^{{\}bf 1.}~{\rm ESR}~{\rm value}~{\rm is}~{\rm dependent}~{\rm upon}~{\rm frequency}~{\rm of}~{\rm oscillation}$





LVCMOS DC Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input High Voltage	Single-ended inputs, except SMBus	0.75 V _{DD}		V _{DD} +0.3	V
V_{IM}	Input Mid Voltage	SS_SEL_TRI	$0.4 V_{ m DD}$	$0.5 V_{ m DD}$	$0.6 V_{ m DD}$	V
V_{IL}	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 V _{DD}	V
I_{IH}	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			5	μΑ
I_{IL}	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-5			μА
I _{IH}	Input High Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = V_{DD}$			50	μА
I_{IL}	Input Low Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = 0V$	-50			μА
V _{OH}	Output High Voltage	REFOUT, except SMBus; I _{OH} = -2mA	0.8 x V _{DD} _ refout			V
V _{OL}	Output Low Voltage	REFOUT, except SMBus; $I_{OL} = 2mA$			0.2 x V _{DD} _ REFOUT	V
R _{OUT}	CMOS Output impedance			20		Ω
C _{IN}	Input Capacitance		1.5		5	pF





LVCMOS AC Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f _{INPUT}	Input Frequency	XTAL_IN/CLK		25		MHz
t _{RIN}	Input rise time	Single-ended inputs			5	ns
t_{FIN}	Input fall time	Single-ended inputs			5	ns
t_{STAB}	Clock stabilization	From Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.75	1	ms
t _{OELAT}	Output enable latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
t _{PDLAT}	PD# de-assertion	Differential outputs enable after PD# deassertion		20	300	us
t _{PERIOD}	REFOUT clock period	REFOUT, assume input is at 25MHz		40		ns
f_{ACC}	REFOUT frequency accuracy ⁽¹⁾	REFOUT, long term accuracy to input		0		ppm
	REFOUT slew rate ⁽¹⁾	Byte 3 = 1F, 20% to 80% of V _{DDREF}	0.9	1.4	2	V/ns
4.		Byte 3 = 5F, 20% to 80% of V _{DDREF}	1.5	2.4	3.2	V/ns
$t_{\rm SLEW}$	REPOUT siew rate	Byte 3 = 9F, 20% to 80% of V _{DDREF}	2	3	5 5 1 3 300 2 3.2 3.8 4 55 +2 150 0.3 1.5 -135	V/ns
		Byte 3 = DF, 20% to 80% of V _{DDREF}	2.3	3.2		V/ns
t_{DC}	REFOUT Duty Cycle ⁽¹⁾	$V_T = V_{DD} / 2 V$, driven by a Xtal	45	50	55	%
t _{DCDIS}	REFOUT Duty Cycle Distortion	$V_T = V_{DD} / 2$ V, driven by an external source	-2	0	+2	%
t _{JITCC}	REFOUT cycle-cycle jitter	$V_T = V_{DD} / 2V$, driven by a Xtal	_	70	150	ps
4	DEFOLIT Phase Litter DMC	12kHz to 5MHz, SSC off, driven by a Xtal	_	0.16	0.3	ps
tJITPH	REFOUT Phase Jitter, RMS	12kHz to 5MHz, SSC on, driven by a Xtal	_	0.9	3 300 2 3.2 3.8 4 55 +2 150 0.3 1.5 -135	ps
4	Naisa flagr	1kHz offset, driven by a Xtal	_	-149	-135	dBc/Hz
t _{JITN}	Noise floor	10kHz offset to Nyquist, driven by a Xtal	_	-158	5 1 3 300 2 3.2 3.8 4 55 +2 150 0.3 1.5 -135	dBc/Hz

8

Note:

1. Guaranteed by design and characterization, not 100% tested in production





HCSL Output Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V _{OH}	Output Voltage High ⁽¹⁾	Statistical measurement on single-ended	660	784	850	mV
V _{OL}	Output Voltage Low ⁽¹⁾	signal using oscilloscope math function	-150		150	mV
V _{OMAX}	Output Voltage Maximum ⁽¹⁾	Measurement on single ended signal using		816	1150	mV
V _{OMIN}	Output Voltage Minimum ⁽¹⁾	absolute value	-300	-42		mV
V _{OC}	Output Cross Voltage(1,2,4)		250	430	550	mV
DV _{OC}	V _{OC} Magnitude Change ^(1,2,5)			12	140	mV

Note:

- 1. At default SMBUS amplitude settings
- 2. Guaranteed by design and characterization, not 100% tested in production
- 3. Measured from differential waveform
- 4. This one is defined as voltage where Q+ = Q- measured on a component test board and only applied to the differential rising edge
- 5. The total variation of all Vcross measurements in any particular system. This is a subset of Vcross_min/max allowed.

HCSL Output AC Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
f _{OUT}	Output Frequency			100		MHz
	Slew rate ^(1,2,3)	Scope averaging on fast setting	2.5	3.2	4	V/ns
t _{RF}	Siew rate	Scope averaging on slow setting	2.2	3	3.7	V/ns
Dt _{RF}	Slew rate matching ^(1,2,4)	Scope averaging on	_	7	15	%
t_{DC}	Duty Cycle ^(1,2)	Measured differentially, PLL Mode	45	50	55	%
t _{SKEW}	Output Skew ^(1,2)	Averaging on, $V_T = 50\%$		20	50	ps
tj _{c-c}	Cycle to cycle jitter ^(1,2)			20	50	ps





HCSL Output AC Characteristics Cont.

Symbol	Parameters	Condition	Min.	Тур.	Max	Spec Limit	Units
		PCIe Gen 1 ⁽⁶⁾		20	30	86	ps(p-p)
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz		0.08	0.1	3.0	ps
		PCIe Gen 2 High Band, 1.5MHz < f < Nyquist (50MHz)		0.99	1.3	3.1	ps
tj _{PHASE}	Integrated Phase Jitter (RMS) ^(1,5)	PCIe Gen3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)		0.32	0.42	1.0	ps
	(IIII)	PCIe Gen3 Separate Reference No Spread (PLL BW of 2-4 or 2-5MHz, CDR =10 MHz)		0.16	0.21	0.7	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)		0.32	0.4	0.5	ps
		PCIe Gen 5 ⁽⁷⁾ (PLL BW of 500k to 1.8MHz. CDR = 20MHz)		0.02	0.05	0.15	ps
tj _{PH} - SRISG2	Integrated Phase Jitter (RMS), -0.25% Spread	PCIe Gen 2, Separate Reference Independent Spread (PLL BW of 16MHz, CDR=5MHz)		0.6	0.92	2	ps
tj _{PH} - SRISG3	Integrated Phase Jitter (RMS), -0.25% Spread	PCIe Gen 3, Separate Reference Independent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)		0.32	0.4	0.7	ps
tj _{PH} - SRISG2	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 2, Separate Reference Independent Spread (PLL BW of 16MHz, CDR=5MHz)		0.8	1.1	2	ps
tj _{PH} - SRISG3	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 3, Separate Reference Independent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)		0.35	0.6	0.7	ps

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. Measured from differential waveform.
- $3. \ Slew\ rate\ is\ measured\ through\ the\ Vswing\ voltage\ range\ centered\ around\ differential\ 0V,\ within\ \pm 150mV\ window.$
- 4. It is measured using a ± 75 mV window centered on the average cross point.
- $5.\ See \ http://www.pcisig.com\ for\ complete\ specs.$
- 6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of 10^{-12} .
- 7. PCIe Gen 5 v0.9 specification.





Differential Output Clock Periods - Spread Spectrum Disabled

			Mea	surement Wir	ndow			
Center	1 clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

Differential Output Clock Periods - Spread Spectrum Enabled

			Mea	surement Wir	ndow			
Center	1 clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

^{1.} Guaranteed by design and characterization—not 100% tested in production.

 $^{2. \} All \ long \ term \ accuracy \ and \ clock \ period \ specifications \ are \ guaranteed \ assuming \ REF \ is \ trimmed \ to \ 25MHz.$





SMBus Serial Data Interface

PI6CG33201C is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

Address Assignment

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

How to Write

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

How to Read

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

8 bits	1 bit	1 bit
Data Byte	NAck	Stop bit
(N+X-1)	NACK	Stop bit

Byte 0: Output Enable Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	Reserved			0		
3	Reserved			0		
2	Q1_OE	Q1 output enable	RW	1	See B11[1:0]	Pin Control
1	Q0_OE	Q0 output enable	RW	1	See B11[1:0]	Pin Control
0	Reserved			0		

 $^{1.\} A\ low\ on\ these\ bits\ will\ override\ the\ OE\#\ pins\ and\ force\ the\ differential\ outputs\ to\ the\ state\ indicated\ by\ B11[1:0]\ (Low/\ Low\ default)$





Byte 1: SS Spread Spectrum and Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL_	_TRI = '0',
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'10' for SS_SEL_ '11' for SS_SEL_	
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount
4	SSENSW1	SS enable SW control Bit1	RW ⁽¹⁾	0	'00' = SS off, '01	' = -0.25% SS,
3	SSENSW0	SS enable SW control Bit0	RW ⁽¹⁾	0	'10' = SS off, '11'	= -0.5% SS
2	Reserved			1		
1	Amplitude1	Control output amplituda	RW	1	'00' = 0.6V, '01' =	= 0.68V, '10' =
0	Amplitude0	Control output amplitude	RW	0	0.75V, '11' = 0.85	5V

Byte 2: Differential Output Slew Rate Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Reserved			1		
2	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting
1	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting
0	Reserved			1		

^{1.} Spread must be selected OFF or ON with the hardware latch pin. These bits should not be used to turn spread ON or OFF after power up. These bits can be used to change the spread amount, and B1[5] must be set to a 1 for these bits to have any effect on the part. If These bits are used to turn spread OFF or ON, the system will need to be reset.





Byte 3: REF Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	DEECLEMD ATE	Cl. 4 4 16 DEE	RW	0	'00' = 1.4V/ns '0	1' = 2.4V/ns,
6	REFSLEWRATE	Slew rate control for REF	RW	1	'10' = 3V/ns, '11'	= 3.2V/ns
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = Dis- abled in PD state ⁽¹⁾	REF = run- ning in PD state
4	REF_OE	Output enable for REF	RW	1	REF = Dis- abled ⁽¹⁾	REF = run- ning
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

Note:

Byte 4: Reserved

Bit	Control Function	Description	Type	Power Up Condition	0	1
7:0	Reserved			0x40		

Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0 1	
7	RID3	Revision ID	R	0		
6	RID2		R	0		
5	RID1		R	0	rev = 0000	
4	RID0		R	0		
3	PVID3		R	0		
2	PVID2	W 1 15	R	0	Diodes = 0011	
1	PVID1	Vendor ID	R	1		
0	PVID0		R	1		

^{1.} The disabled state depends on Byte11[1:0]. '00' = Low, '01'=HiZ, '10'=Low, '11'=High





Byte 6: Device Type/Device ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1	
7	DTYPE1	Desire	R	0	'00' = CG, '01' = ZDB,		
6	DTYPE0	Pevice type	R	0	'10' = Reserve, '11' = NZDB		
5	DID5	1	R	0	- - 000010 binary, 02Hex		
4	DID4		R	0			
3	DID3	Device ID	R	0			
2	DID2	Device ID	R	0			
1	DID1		R	1			
0	DID0		R	0	1		

Byte 7: Byte Count Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	BC4		RW	0		
3	BC3		RW	1	Writing to this register will configure how many bytes w	
2	BC2	Byte count programming	RW	0		
1	BC1		RW	0	be read back, do	efault is 8 bytes
0	BC0		RW	0		

Byte 8 and 9: Reserved

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved			B8: 0x36 B9:0x00		

Byte 10: PD Restore

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	PD Restore	PD Restore to default configuration	RW	1	Clear PD Config	Keep PD Config
5:0	Reserved			0		





Byte 11: Stop Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:2	Reserved			0		
1	STP1	True/ Compliment DIF Output Disable Sate	RW	0	00= Low/Low	10= High/ Low
0	STP0		RW	0	01= HiZ/HiZ	11= Low/High

Byte 12: Impedance Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Q0_Zout1	Q0 Zout	RW			
6	Q0_Zout0	Q0 Zout	RW			
5	Reserved			00 = Reserved		
4	Reserved			10	$01 = 85\Omega$	
3	Reserved			10	$10 = 100\Omega$	
2	Reserved	Reserved			11 = Reserved	
1	Reserved	Reserved				
0	Reserved					

Byte 13: Impedance Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved					
6	Reserved					
5	Reserved				00 = Reserved	
4	Reserved			10	$01 = 85\Omega$	
3	Q1_Zout1	Q1 Zout	RW	10	$10 = 100\Omega$	
2	Q1_Zout0	Q1 Zout	RW		11 = Reserved	
1	Reserved					
0	Reserved					





Byte 14: OE Termination Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	OE0_term1	OE0 Pull up or down	RW	0	00=None	10= Pullup
6	OE0_term0	OE0 Pull up or down	RW	1	01=Pulldown	11=Pullup and Down
5	Reserved			0		
4	Reserved			1		
3	Reserved			0		
2	Reserved			1		
1	Reserved			0		
0	Reserved			1		

Byte 15: OE Termination Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			1		
5	Reserved			0		
4	Reserved			1		
3	OE1_term1	OE1 Pull up or down	RW	0	00=None	10= Pullup
2	OE1_term0	OE1 Pull up or down	RW	1	01=Pulldown	11=Pullup and Down
1	Reserved			0		
0	Reserved			1		

Byte 16: Power Good Termination Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:2	Reserved			0x09		
1	PWRGD_PD1	Clark Dance Card and Dance Dance Date of Dance	RW	1	00=None	10= Pullup
0	PWRGD_PD0	Clock Power Good and Power Down Pull up or Pull down	RW	0	01=Pulldown	11=Pullup and Down

17





Byte 17: Reserved

Byte 18: Enable Pin Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	OE1_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
4	Reserved			0		
3	OE0_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
2	Reserved			0		
1	Reserved			0		
0	Reserved			0		

Byte 19: Power Down Pin Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:1	Reserved			0		
0	PWRGD_PD	PWRGD_PD Active via Pull up or Pull down	RW	0	Power Down = Low	Power Down = High

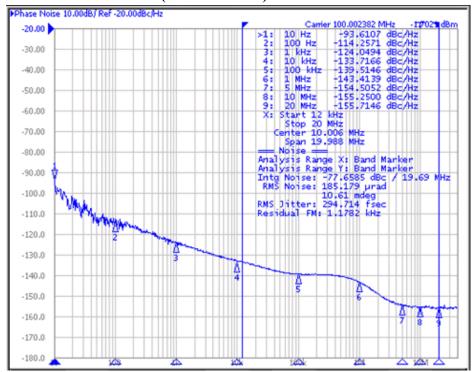
18



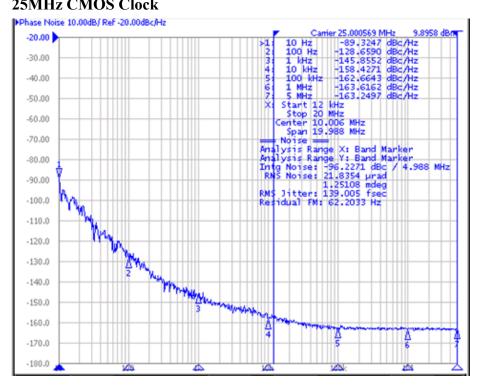


Plots

100MHz HCSL Clock (12k to 20MHz)



25MHz CMOS Clock



19



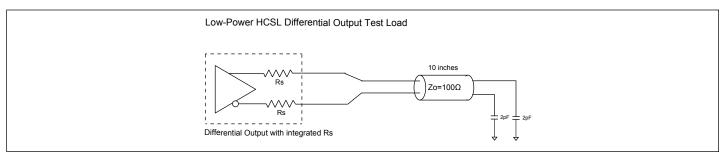


Figure 1. Low Power HCSL Test Circuit

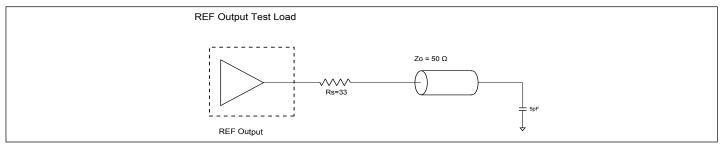


Figure 2. CMOS REF Test Circuit

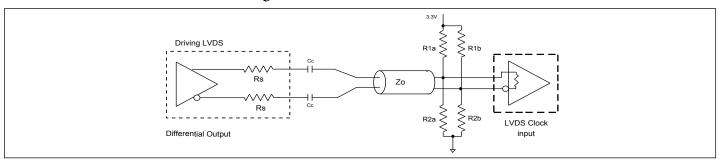


Figure 3. Differential Output Driving LVDS

Alternate Differential Output Terminations (Zo = 1000)

Component	Receiver with termination	Receiver without termination	Unit
R_{1a}, R_{1b}	10,000	140	Ω
R_{2a}, R_{2b}	5,600	75	Ω
$C_{\mathbb{C}}$	0.1	0.1	μF
V_{CM}	1.2	1.2	V

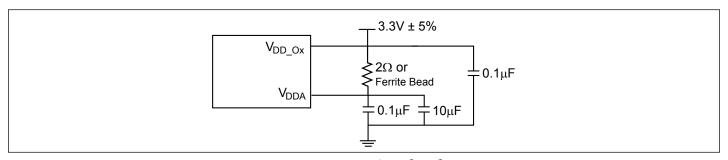


Figure 4. Power Supply Filter

www.diodes.com

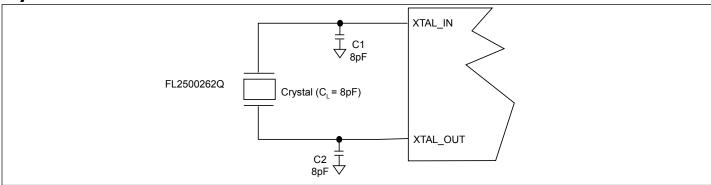




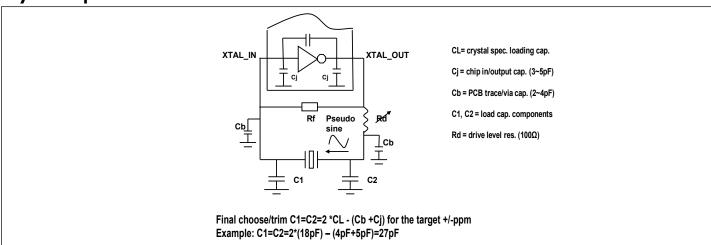
Crystal circuit connection

The following diagram shows PI6CG33201C crystal circuit connection with a parallel crystal. For the CL=8pF crystal, it is suggested to use C1=8pF, C2=8pF. C1 and C2 can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

Crystal Oscillator Circuit



Crystal Capacitor Calculation



Recommended Crystal Specification

Diodes recommends:

- a) FL2500217, SMD 3.2x2.5(4P), 25MHz, CL=8pF, +/-20ppm, https://www.diodes.com/assets/Datasheets/FL.pdf
- b) FH2500016, SMD 2.5x2.0(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FH.pdf
- c) FW2500031, SMD 2.0x1.6(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FW.pdf
- d) US2500003, SMD 1.6x1.2(4P), 25MHz, CL=12pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/US.pdf





Thermal Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
θ_{JA}	Thermal Resistance Junction to Ambient	Still air			54.4	°C/W
$\theta_{ m JC}$	Thermal Resistance Junction to Case				40.8	°C/W

Part Marking

6CG332 01CZDIE YYWWXX

Y: Year

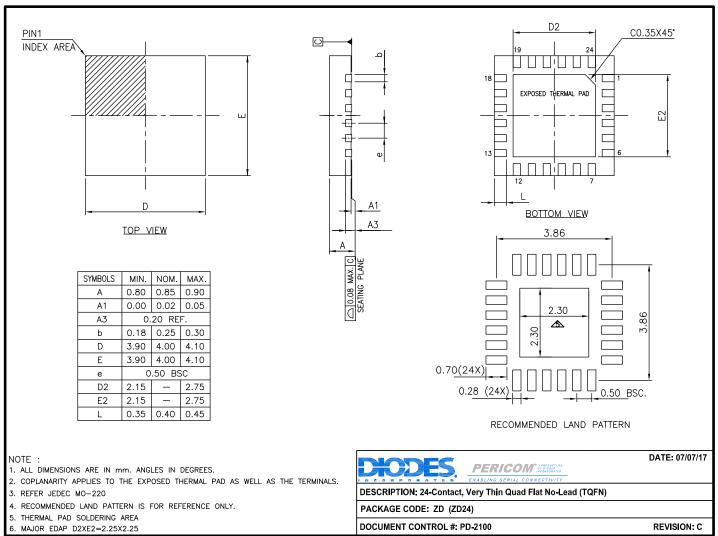
W: Workweek

1st X: Assembly Code 2nd X: Fab Code





Packaging Mechanical: 24-TQFN (ZD)



17-0533

For latest package info.

please check: http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/

Ordering Information

Ordering Code	Package Code	Package Description	Pin 1 Location
PI6CG33201CZDIEX	ZD	24-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Right Corner
PI6CG33201CZDIEX-13R	ZD	24-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Left Corner

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- $2. \ \ See \ https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.$
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. E = Pb-free and Green
- 5. X suffix = Tape/Reel
- 6. For packaging details, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf





IMPORTANT NOTICE

DIODES INCORPORATED MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDS TO THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

Diodes Incorporated and its subsidiaries reserve the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. Diodes Incorporated does not assume any liability arising out of the application or use of this document or any product described herein; neither does Diodes Incorporated convey any license under its patent or trademark rights, nor the rights of others. Any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Diodes Incorporated and all the companies whose products are represented on Diodes Incorporated website, harmless against all damages.

Diodes Incorporated does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel.

Should Customers purchase or use Diodes Incorporated products for any unintended or unauthorized application, Customers shall indemnify and hold Diodes Incorporated and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.

Products described herein may be covered by one or more United States, international or foreign patents pending. Product names and markings noted herein may also be covered by one or more United States, international or foreign trademarks.

This document is written in English but may be translated into multiple languages for reference. Only the English version of this document is the final and determinative format released by Diodes Incorporated.

LIFE SUPPORT

Diodes Incorporated products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Diodes Incorporated. As used herein:

- A. Life support devices or systems are devices or systems which:
 - 1. are intended to implant into the body, or
- 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Customers represent that they have all necessary expertise in the safety and regulatory ramifications of their life support devices or systems, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of Diodes Incorporated products in such safety-critical, life support devices or systems, notwithstanding any devices- or systems-related information or support that may be provided by Diodes Incorporated. Further, Customers must fully indemnify Diodes Incorporated and its representatives against any damages arising out of the use of Diodes Incorporated products in such safety-critical, life support devices or systems.

Copyright © 2016, Diodes Incorporated www.diodes.com